



# SCANBOOSTER II

## Multifunctional JTAG/Boundary Scan Controller



- controller for Embedded Testing and Programming
- high flexibility through multifunctional I/O channels for mixed-signal tests
- modularity and scalability due to configurable TAP Interface Cards
- integrated compact unit controllable via USB 2.0 and GBit-LAN



### Parameters

number of TAP slots	2 (independent and individually configurable with TAP plug-in cards)
maximum TCK frequency	16 MHz (adjustable via software)
parallel I/O channels	32 mixed-signal channels, individually configurable as input, output, tri-state, software programmable VIO 0.9–3.6 V (4 groups with 8 I/O)
maximum number of I/O modules	-
integrated technology	HYSCAN™, ADYCS™

### Embedded Test

- support of latest technologies like Processor Emulation Test, FPGA Assisted Test and Embedded Diagnostics Test
- synchronization with the multi-functional I/O channels and ChipVORX FPGA instruments

### Software

- integration in Embedded JTAG Solutions platform SYSTEM CASCON™
- Plug-and-Play integration in 3rd Party Systems
- open mix of test and programming procedures in one environment

### Performance

- use of state-of-the-art multi-core processors and FPGAs
- simultaneous operation with up to 16 MHz at all TAPs at once
- operation with up to 100 MHz on I/O channels
- support for gang operations

### Embedded Programming

- programming of flash components like NAND, NOR, SPI, I2C, eMMC etc. (also via I/O)
- universal programming of µControllers
- FPGA/PLD programming

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### Adaptability

- easy bridging of distances of up to four meters to the target without TCK reduction
- software parameterizable I/Os (slew rate, impedance, termination)
- software selectable protocols (JTAG, DAP, COP, SWD, UART, BDM, SBW)

### Expandability

- scalable number of one to two TAPs

Made in Germany

